

Notice of References Cited	Application/Control No. 10/823,778		Applicant(s)/Patent Under Reexamination SAMSOONDAR, JAMES	
	Examiner Arlen Soderquist		Art Unit 1797	Page 2 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,597,532	01-1997	Connolly, James	422/58
*	B	US-5,637,505	06-1997	Li et al.	436/8
*	C	US-5,660,791	08-1997	Brenneman et al.	422/58
*	D	US-5,830,134	11-1998	Caputo et al.	600/322
*	E	US-5,872,713	02-1999	Douglas et al.	702/85
*	F	US-6,064,898	05-2000	Aldrich, Thomas K	600/316
*	G	US-6,121,050	09-2000	Han, Chi-Neng Arthur	436/95
*	H	US-6,582,964	06-2003	Samsoondar et al.	436/67
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Aldridge, P. K. et al, Analytical Chemistry 1996, 68, 997-1002.
	V	Chen, C.-S. et al, Applied Spectroscopy 1997, 51, 744-748.
	W	Lin, J. et al, Analytica Chimica Acta 1997, 349, 263-269.
	X	Andrews, D. T. et al, Analytica Chimica Acta 1997, 350, 341-352.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/823,778		Applicant(s)/Patent Under Reexamination SAMSOONDAR, JAMES	
	Examiner Arlen Soderquist		Art Unit 1797	Page 1 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,703,336	11-1972	Rosse et al.	356/39
*	B	US-4,263,512	04-1981	Sagusa et al.	250/373
*	C	US-4,309,384	01-1982	Trod, Ernest	422/64
*	D	US-4,509,859	04-1985	Markart et al.	356/446
*	E	US-4,673,657	06-1987	Christian, Clifford N.	436/501
*	F	US-4,985,205	01-1991	Fritsche et al.	422/56
*	G	US-5,061,632	10-1991	Shepherd et al.	436/66
*	H	US-5,073,029	12-1991	Eberly et al.	356/432
*	I	US-5,075,077	12-1991	Durley et al.	422/56
*	J	US-5,281,395	01-1994	Markart et al.	422/82.05
*	K	US-5,397,538	03-1995	Stark et al.	422/57
*	L	US-5,459,677	10-1995	Kowalski et al.	703/2
*	M	US-5,478,750	12-1995	Bernstein et al.	436/164

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Forina, M. et al, Chemometrics and Intelligent Laboratory Systems 1995, 27, 189-203.
	V	Wang, Z. et al, Analytical Chemistry 1995, 67, 2379-2385.
	W	van de Voort, F. R. et al, Journal of the American Oil Chemists' Society 1995, 72, 873-880.
	X	Bouveresse, E. et al, Analytical Chemistry 1995, 67, 1381-1389.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/823,778	Applicant(s)/Patent Under Reexamination SAMSOONDAR, JAMES	
	Examiner Arlen Soderquist	Art Unit 1797	Page 3 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Swierenga, H. et al, Applied Spectroscopy 1998, 52, 7-16.
	V	Despaigne, F. et al, Applied Spectroscopy 1998, 52, 732-745.
	W	Sum, S. T. et al, Applied Spectroscopy 1998, 52, 869-877.
	X	Sjoblom, J. et al, Chemometrics and Intelligent Laboratory Systems 1998, 44, 229-244.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/823,778	Applicant(s)/Patent Under Reexamination SAMSOONDAR, JAMES	
	Examiner Arlen Soderquist	Art Unit 1797	Page 4 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nevado, J. J. B. et al, Talanta 1999, 48, 895-903.
	V	Ozdemir, D. et al, Applied Spectroscopy 1999, 53, 210-217.
	W	Thomas, E. V., Analytical Chemistry 2000, 72, 2821-2827.
	X	Ulmschneider, M. et al, Analusis 2000, 28, 83-87.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/823,778	Applicant(s)/Patent Under Reexamination SAMSOONDAR, JAMES	
	Examiner Arlen Soderquist	Art Unit 1797	Page 5 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Greensill, C. V. et al, Applied Spectroscopy 2001, 55, 647-653.
	V	Wehlburg, C. M. et al, Applied Spectroscopy 2002, 56, 877-886.
	W	Zhang, L. et al, Analytical Chemistry 2003, 75, 5905-5915.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.